## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | NISHIKAWA ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2001/0050532	12-2001	Eida et al.	313/504
	В	US-2002/0192576	12-2002	Matsuoka et al.	430/7
	С	US-2003/0214248	11-2003	Jinno, Yushi	315/169.3
	D	US-2004/0051448	03-2004	Matsumoto, Shoichiro	313/506
	E	US-2002/0063518	05-2002	Okamoto et al.	313/506
	F	US-2002/0113546	08-2002	Seo et al.	313/504
	G	US-2003/0098645	05-2003	Lee et al.	313/504
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	σ					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	>	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.